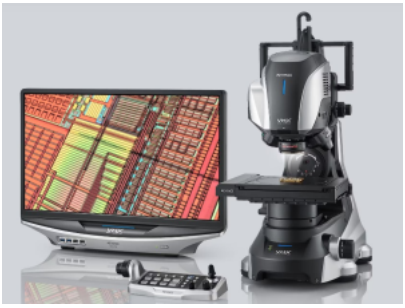
Morphology-SH

Optical Microscope

***Owner:** Tingting Zhang*

***Principle*:**	**Sample surfaces can be analyzed using reflection mode, while the structure of materials can be studied using transmitted light (samples must be a few micrometers thick). A large variety of contrast modes exist to highlight different aspects of material structures, depending on the information needed.**	
***Capabilities*:**	**Multiple function analysis including but not limited as surface structure, flow mark, orientation/distribution of fillers, flash, defect analysis, etc.**	
Asset:		**Keyence VHX-7000 system:** **Observation of samples at higher magnifications (x20-x200,X200–X2000) in reflection or transmission, and digital camera. External handheld lens (x20-x200) for special samples.**
Preparative Techniques:		**Polisher: Struers LaboPol-5** **Polishing machine equipped with an autosampler, to prepare embedded sections and surfaces, with a finish at 1 µm.**

Sinpa Projector_Shrinkage test

***Owner:** Mengjun Guo*

***Principle*:**	**Compare the dimensions of the mold and the color chips, and calculate the shrinkage of the sample.**
***Capabilities*:**	**Support molding processing**

Asset:		**JVB250** **Sample requirements: Color Chips*10** **Color chips dimension:** **60*60*2; 80*80*2; 80*80*1(mm)**